

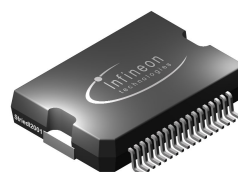
Smart 16-fold Low-Side Switch

Features

- Short Circuit Protection
- Overtemperature Protection
- Overvoltage Protection
- 16 bit Serial Data Input and Diagnostic Output (2 bit/chan. acc. SPI Protocol)
- Direct Parallel Control of Eight channels for PWM Applications
- Parallel Inputs High or Low Active Programmable
- General Fault Flag
- Low Quiescent Current
- Compatible with 3V Microcontrollers
- **Electrostatic discharge (ESD) Protection**

Product Summary

Supply voltage	V_S	4.5 – 5.5V
Drain source clamping voltage	$V_{DS(AZ)max}$	60 V
On resistance	$R_{ON\ 1-8}$	1.0 Ω
	$R_{ON\ 10,11,14,15}$	0.35 Ω
	$R_{ON\ 9,12,13,16}$	0.3 Ω
Output current (Channel 1-8)	$I_{D(NOM)}$	0.5 A
	(Channel 9-16) $I_{D(NOM)}$	1 A



P-DSO 36-12

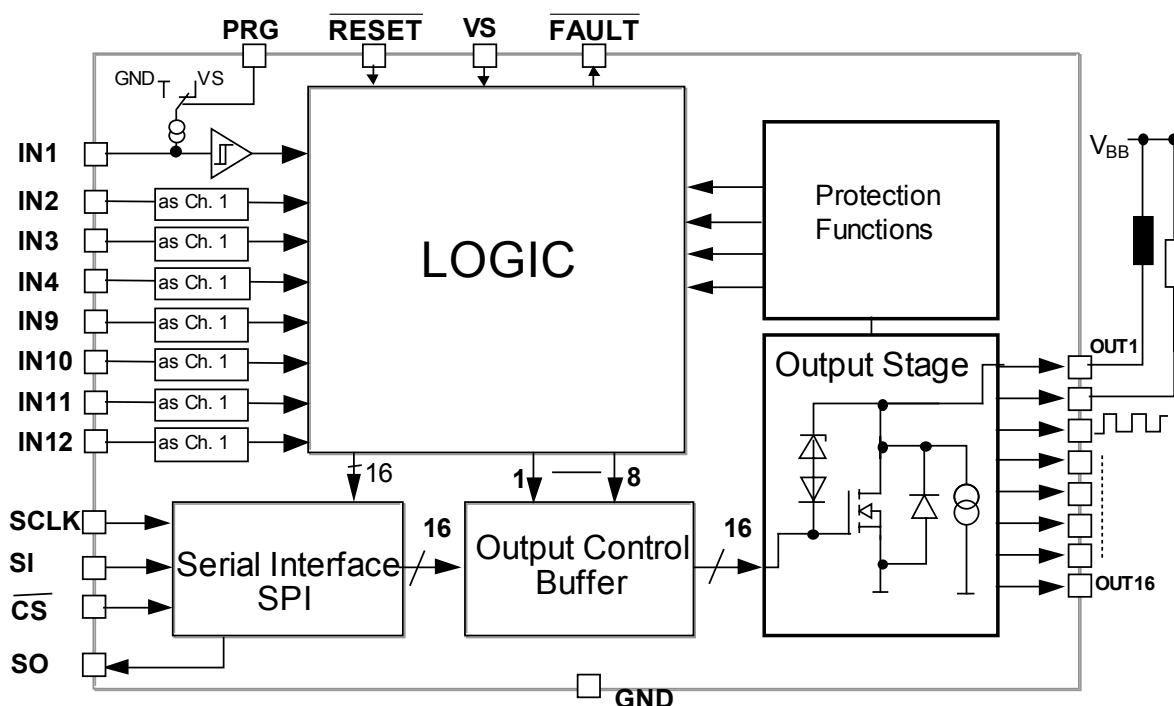
Ordering Code:
Q67007-A9470

Application

- μ C Compatible Power Switch for 12 V and 24 V Applications
- Switch for Automotive and Industrial System
- Solenoids, Relays and Resistive Loads
- Robotic Controls

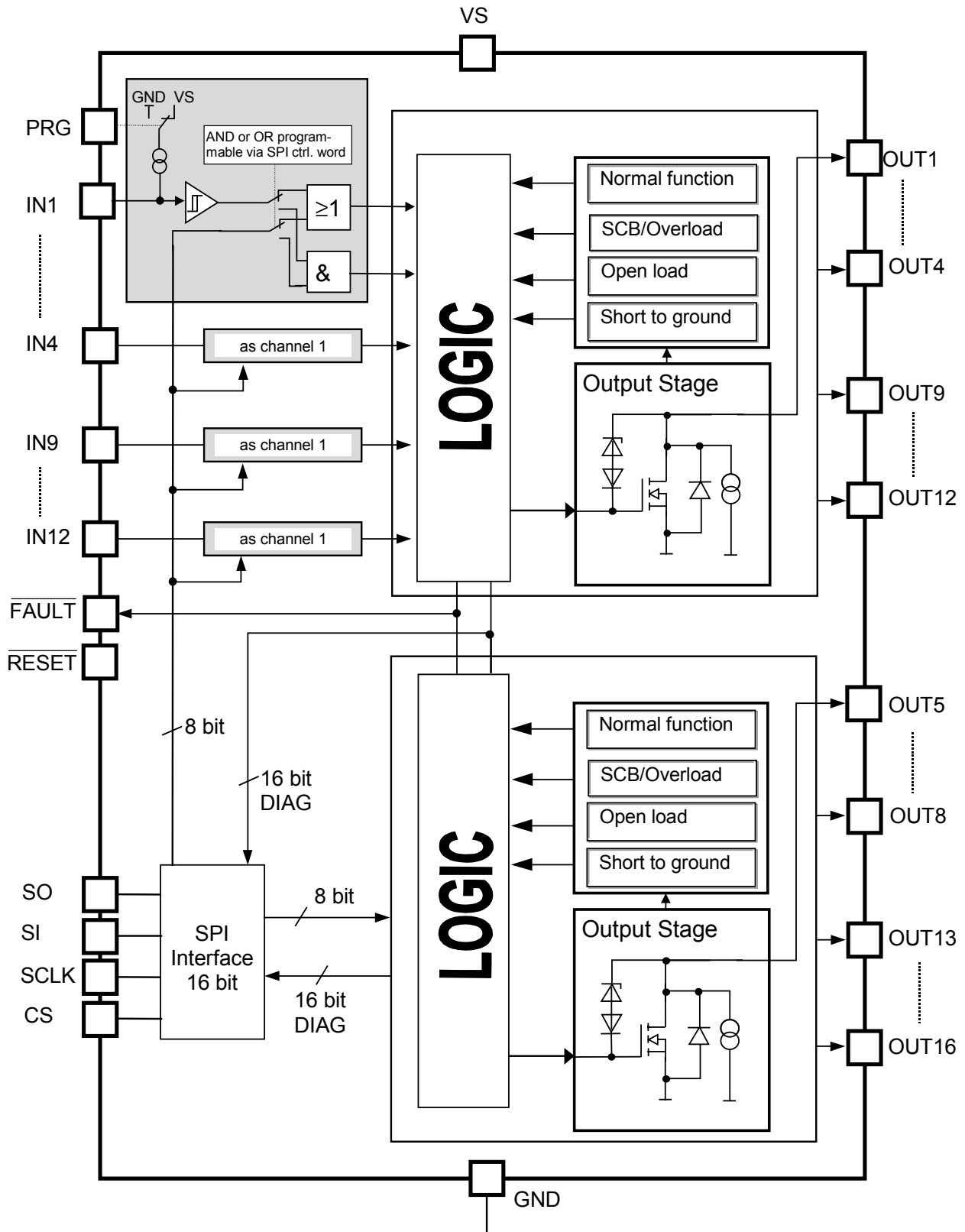
General description

16-fold Low-Side Switch (8 x 1.3 Ω , 4 x 0.4 Ω , 4 x 0.35 Ω) in Smart Power Technology (SPT) with a **Serial Peripheral Interface (SPI)** and 16 open drain DMOS output stages. The TLE 6240 GP is protected by embedded protection functions and designed for automotive and industrial applications. The output stages are controlled via SPI Interface. Additionally 8 channels can be controlled direct in parallel for PWM applications. Therefore the TLE 6240 GP is particularly suitable for engine management and powertrain systems, safety and body applications.



Detailed Block Diagram

All 16 channels can be controlled via the serial interface (SPI). In addition to the serial control it is possible to con-



trol channel 1 to 4 and 9 to 12 direct in parallel with a separate input pin. The parallel input signal is either ORed or ANDed with the respective SPI data bit. This boolean operation can be programmed via SPI control byte (see chapter "Functional Description"). The SPI interface also performs a diagnostic information for each channel.

Pin Description

Pin	Symbol	Function
1	GND	Ground
2	OUT9	Power Output Channel 9
3	OUT10	Power Output Channel 10
4	OUT1	Power Output Channel 1
5	OUT2	Power Output Channel 2
6	IN1	Input Channel 1
7	IN2	Input Channel 2
8	VS	Supply Voltage
9	RESET	Reset
10	CS	Chip Select
11	PRG	Program (inputs high or low-active)
12	IN3	Input Channel 3
13	IN4	Input Channel 4
14	OUT3	Power Output Channel 3
15	OUT4	Power Output Channel 4
16	OUT11	Power Output Channel 11
17	OUT12	Power Output Channel 12
18	GND	Ground
19	GND	Ground
20	OUT13	Power Output Channel 13
21	OUT14	Power Output Channel 14
22	OUT5	Power Output Channel 5
23	OUT6	Power Output Channel 6
24	IN9	Input Channel 9
25	IN10	Input Channel 10
26	FAULT	General Fault Flag
27	SO	Serial Data Output
28	SCLK	Serial Clock
29	SI	Serial Data Input
30	IN11	Input Channel 11
31	IN12	Input Channel 12
32	OUT7	Power Output Channel 7
33	OUT8	Power Output Channel 8
34	OUT15	Power Output Channel 15
35	OUT16	Power Output Channel 16
36	GND	Ground

Pin Configuration (Top view)

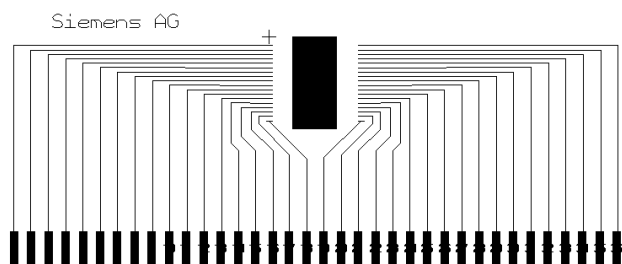
GND	1●	36	GND
OUT9	2	35	OUT16
OUT10	3	34	OUT15
OUT1	4	33	OUT8
OUT2	5	32	OUT7
IN1	6	31	IN12
IN2	7	30	IN11
VS	8	29	SI
RESET	9	28	SCLK
CS	10	27	SO
PRG	11	26	FAULT
IN3	12	25	IN10
IN4	13	24	IN9
OUT3	14	23	OUT6
OUT4	15	22	OUT5
OUT11	16	21	OUT14
OUT12	17	20	OUT13
GND	18	19	GND

Power SO 36

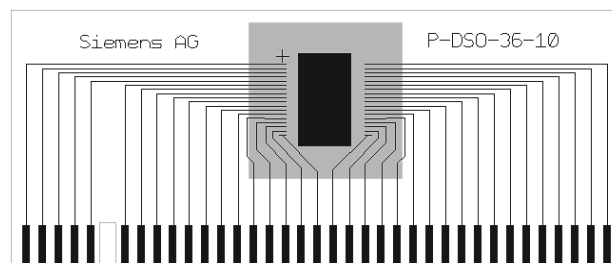
Heat Slug internally connected to ground pins

Maximum Ratings for $T_j = -40^{\circ}\text{C}$ to 150°C

Parameter	Symbol	Values	Unit
Supply Voltage	V_S	-0.3 ... +7	V
Continuous Drain Source Voltage (OUT1...OUT16)	V_{DS}	45	V
Input Voltage, All Inputs and Data Lines	V_{IN}	- 0.3 ... + 7	V
Load Dump Protection $V_{Load\ Dump} = U_P + U_S$; $U_P = 13.5\text{ V}$ $R_l^{1)} = 2\ \Omega$; $t_d = 400\text{ms}$; IN = low or high Channel 1-8 with Automotive Relay $R_L = 65\ \Omega$ Channel 9-16 with Automotive Injector Valve $R_L = 14\ \Omega$ $R_l = 2\ \Omega$; $t_d = 400\text{ms}$; IN = low or high Channel 1-8 with Load $R_L = 24\ \Omega$ Channel 9-16 with Load $R_L = 6.8\ \Omega$	$V_{Load\ Dump}^{2)}$	90 65 65 50	V
Output Current per Channel (see el. characteristics)	$I_{D(lim)}$	$I_{D(lim)\ min}$	A
Output Current per Channel @ $T_A = 25^{\circ}\text{C}$ (All 16 Channels ON; Mounted on PCB) ³⁾	I_{D1-8} I_{D9-16}	0.3 0.5	A
Output Current (Max. total current of all channels on; Heat Sink required)	I_{Dmax}	14	A
Single Pulse Inductive Energy (internal clamping) $T_J = 25^{\circ}\text{C}$, $I_{D1-8} = 0.5\text{ A}$, $I_{D9-16} = 1\text{ A}$	E_{AS}	50	mJ
Power Dissipation (DC, mounted on PCB) @ $T_A = 25^{\circ}\text{C}$	P_{tot}	3.3	W
Electrostatic Discharge Voltage (Human Body Model) according to MIL STD 883D, method 3015.7 and EOS/ESD assn. standard S5.1 - 1993	V_{ESD}	2000	V
DIN Humidity Category, DIN 40 040		E	
IEC Climatic Category, DIN IEC 68-1		40/150/56	
Thermal Resistance junction - case (die soldered on heat slug) junction - ambient @ min. footprint junction - ambient @ 6 cm^2 cooling area with heat pipes	R_{thJC} R_{thJA}	1.5 50 38	K/W



Minimum footprint


 PCB with heat pipes,
back side 6 cm^2 cooling area

¹⁾ R_l = internal resistance of the load dump test pulse generator LD200

²⁾ $V_{LoadDump}$ is setup without DUT connected to the generator per ISO 7637-1 and DIN 40 839.

³⁾ Output current rating so long as maximum junction temperature is not exceeded. At $T_A = 125^{\circ}\text{C}$ the output current has to be calculated using R_{thJA} according mounting conditions.

Electrical Characteristics

Parameter and Conditions $V_S = 4.5$ to 5.5 V ; $T_J = -40$ °C to $+150$ °C; Reset = H (unless otherwise specified)	Symbol	Values			Unit
		min	typ	max	

1. Power Supply, Reset

Supply Voltage ⁴	V_S	4.5	--	5.5	V
Supply Current	I_S	--	5	10	mA
Supply Current in Standby Mode (RESET = L)	$I_{S(stdy)}$	--	10	50	μA
Minimum Reset Duration (After a reset all parallel inputs are ORed with the SPI data bits)	$t_{Reset,min}$	10	--	--	μs

2. Power Outputs

ON Resistance $V_S = 5$ V Channel 1 ... 8	$T_J = 25$ °C $T_J = 150$ °C	$R_{DS(ON)}$	-- --	1 1.7	1.3 2.2	Ω
ON Resistance $V_S = 5$ V Channel 10, 11, 14, 15	$T_J = 25$ °C $T_J = 150$ °C	$R_{DS(ON)}$	-- --	0.35 0.60	0.40 0.70	Ω
ON Resistance $V_S = 5$ V Channel 9, 12, 13, 16	$T_J = 25$ °C $T_J = 150$ °C	$R_{DS(ON)}$	-- --	0.30 0.50	0.35 0.60	Ω
Output Clamping Voltage Output OFF	Channel 1-8 Channel 9-16	$V_{DS(AZ)}$	45 45	50 52,5	60 60	V
Current Limit	Channel 1...8 Channel 9...16	$I_{D(lim)}$	1 3	1.5 4.5	2 6	A
Output Leakage Current	$V_{Reset} = L$	$I_{D(Ikg)}$	--	--	10	μA
Turn-On Time	$I_D = 0.5$ A, resistive load	t_{ON}	--	6	12	μs
Turn-Off Time	$I_D = 0.5$ A, resistive load	t_{OFF}	--	6	12	μs

3. Digital Inputs

Input Low Voltage	V_{INL}	- 0.3	--	1.0	V
Input High Voltage	V_{INH}	2.0	--	--	V
Input Voltage Hysteresis	V_{INHys}	50	100	200	mV
Input Pull Down/Up Current (IN1...4, IN9...12) $V_{IN} = 5$ V	$I_{IN(1..4,9...12)}$	20	50	100	μA
PRG, Reset Pull Up Current	$I_{IN(PRG,Res)}$	20	50	100	μA
Input Pull Down Current (SI, SCLK)	$I_{IN(SI,SCLK)}$	10	20	50	μA
Input Pull Up Current ($\overline{CS}$)	$I_{IN(CS)}$	10	20	50	μA

4. Digital Outputs (SO, FAULT)

SO High State Output Voltage	$I_{SOH} = 2$ mA	V_{SOH}	$V_S - 0.4$	--	--	V
SO Low State Output Voltage	$I_{SOL} = 2.5$ mA	V_{SOL}	--	--	0.4	V
Output Tri-state Leakage Current	$\overline{CS} = H, 0 \leq V_{SO} \leq V_S$	I_{SOLkg}	-10	0	10	μA
FAULT Output Low Voltage	$I_{FAULT} = 1.6$ mA	V_{FAULTL}	--	--	0.4	V

⁴ For $V_S < 4.5$ V the power stages are switched according the input signals and data bits or are definitely switched off. This undervoltage reset gets active at $V_S = 3$ V (typ. value) and is guaranteed by design.

Electrical Characteristics cont.

Parameter and Conditions $V_S = 4.5$ to 5.5 V ; $T_j = -40$ °C to $+150$ °C ; Reset = H (unless otherwise specified)	Symbol	Values			Unit
		min	typ	max	

5. Diagnostic Functions

Open Load Detection Voltage	$V_{DS(OL)}$	$V_S - 2.5$	$V_S - 2$	$V_S - 1.3$	V
Output Pull Down Current $V_{Reset} = H$	$I_{PD(OL)}$	50	90	150	µA
Fault Delay Time	$t_{d(fault)}$	50	100	200	µs
Short to Ground Detection Voltage	$V_{DS(SHG)}$	$V_S - 3.3$	$V_S - 2.9$	$V_S - 2.5$	V
Short to Ground Detection Current $V_{Reset} = H$	I_{SHG}	-50	-100	-150	µA
Overload Detection Threshold	$I_{D(lim)} 1...8$	1	1.3	2	A
	$I_{D(lim)} 9...16$	3	4	6	
Overtemperature Shutdown Threshold ⁵ Hysteresis ⁵	$T_{th(sd)}$	170	--	200	°C
	T_{hys}	--	10	--	K

6. SPI-Timing

Serial Clock Frequency (depending on SO load)	f_{SCK}	DC	--	5	MHz
Serial Clock Period (1/fclk)	$t_{p(SCK)}$	200	--	--	ns
Serial Clock High Time	t_{SCKH}	50	--	--	ns
Serial Clock Low Time	t_{SCKL}	50	--	--	ns
Enable Lead Time (falling edge of $\overline{CS}$ to rising edge of CLK)	t_{lead}	200	--	--	ns
Enable Lag Time (falling edge of CLK to rising edge of $\overline{CS}$)	t_{lag}	200	---	--	ns
Data Setup Time (required time SI to falling of CLK)	t_{SU}	20	--	--	ns
Data Hold Time (falling edge of CLK to SI)	t_H	20	--	--	ns
Disable Time @ $C_L = 50$ pF ⁵	t_{DIS}	--	--	150	ns
Transfer Delay Time ⁶ ($\overline{CS}$ high time between two accesses)	t_{dt}	200	--	--	ns
Data Valid Time	t_{valid}	$C_L = 50$ pF ⁵	--	--	100
		$C_L = 100$ pF ⁵	--	--	120
		$C_L = 220$ pF ⁵	--	--	150

⁵ This parameter will not be tested but guaranteed by design

⁶ This time is necessary between two write accesses to control e.g. channel 1 to 8 during the first access and channel 9 to 16 during the second access. To get the correct diagnostic information, the transfer delay time has to be extended to the maximum fault delay time $t_{d(fault)max} = 200\mu s$.

Functional Description

The TLE 6240 GP is an 16-fold low-side power switch which provides a serial peripheral interface (SPI) to control the 16 power DMOS switches, and diagnostic feedback. The power transistors are protected against short to V_{BB} , overload, overtemperature and against over-voltage by active zener clamp.

The diagnostic logic recognizes a fault condition which can be read out via the serial diagnostic output (SO).

Circuit Description

Power Transistor Protection Functions⁷⁾

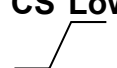
Each of the 16 output stages has its own zener clamp, which causes a voltage limitation at the power transistor when solenoid loads are switched off. The outputs are provided with a current limitation set to a minimum of 1 A for channels 1 to 8 and 3 A for channels 9 to 16.

Each output is protected by embedded protection functions. In the event of an overload or short to supply, the current is internally limited and the corresponding bit combination is set (early warning). If this operation leads to an overtemperature condition, a second protection level (about 170 °C) will change the output into a low duty cycle PWM (selective thermal shut-down with restart) to prevent critical chip temperatures.

SPI Signal Description

$\overline{CS}$ - Chip Select. The system microcontroller selects the TLE 6240 GP by means of the $\overline{CS}$ pin. Whenever the pin is in a logic low state, data can be transferred from the μC and vice versa.

$\overline{CS}$ High to Low transition:  - Diagnostic status information is transferred from the power outputs into the shift register.
 - Serial input data can be clocked in from then on.
 - SO changes from high impedance state to logic high or low state corresponding to the SO bits.

$\overline{CS}$ Low to High transition:  - Transfer of SI bits from shift register into output buffers.

To avoid any false clocking the serial clock input pin SCLK should be logic low state during high to low transition of $\overline{CS}$. When $\overline{CS}$ is in a logic high state, any signals at the SCLK and SI pins are ignored and SO is forced into a high impedance state.

SCLK - Serial Clock. The system clock pin clocks the internal shift register of the TLE 6240 GP. The serial input (SI) accepts data into the input shift register on the falling edge of SCLK while the serial output (SO) shifts diagnostic information out of the shift register on the

⁷⁾ The integrated protection functions prevent an IC destruction under fault conditions and may not be used in normal operation or permanently

rising edge of serial clock. It is essential that the SCLK pin is in a logic low state whenever chip select $\overline{CS}$ makes any transition.

SI - Serial Input. Serial data bits are shifted in at this pin, the most significant bit first. SI information is read in on the falling edge of SCLK. Input data is latched in the shift register and then transferred to the control buffer of the output stages.

The input data consist of 16 bit, made up of one control byte and one data byte. The control byte is used to program the device, to operate it in a certain mode as well as providing diagnostic information (see page 14). The eight data bits contain the input information for the eight channels, and are high active.

SO - Serial Output. Diagnostic data bits are shifted out serially at this pin, the most significant bit first. SO is in a high impedance state until the $\overline{CS}$ pin goes to a logic low state. New diagnostic data will appear at the SO pin following the rising edge of SCLK.

RESET - Reset pin. If the reset pin is in a logic low state, it clears the SPI shift register and switches all outputs OFF. An internal pull-up structure is provided on chip.

Output Stage Control

The 16 outputs of the TLE 6240 GP can be controlled via serial interface. Additionally eight of these 16 channels can alternatively be controlled in parallel (Channel 1 to 4 and 9 to 12) for PWM applications.

Parallel Control

A Boolean operation (either AND or OR) is performed on each of the parallel inputs and respective SPI data bits, in order to determine the states of the respective outputs. The type of Boolean operation performed is programmed via the serial interface.

The parallel inputs are high or low active depending on the PRG pin. If the parallel input pins are not connected (independent of high or low activity) it is guaranteed that the outputs 1 to 4 and 9 to 12 are switched off. The PRG pin itself is internally pulled up when it is not connected.

PRG - Program pin.	PRG = High (V_S):	Parallel inputs Channel 1 to 4 and 9 to 12 are high active
	PRG = Low (GND):	Parallel inputs Channel 1 to 4 and 9 to 12 are low active.

Serial Control of the Outputs: SPI protocol

Each output is independently controlled by an output latch and a common reset line, which disables all outputs. The Serial Input (SI) is read on the falling edge of the serial clock. A logic high input 'data bit' turns the respective output channel ON, a logic low 'data bit' turns it OFF. $\overline{CS}$ must be low whilst shifting all the serial data into the device. A low-to-high transition of $\overline{CS}$ transfers the serial data input bits to the output control buffer.

The 16 channels of the TLE 6240 GP are divided up into two parts for the control of the outputs (ON, OFF) and the diagnosis information.

Channel 1 to 8:

Serial Input (SI) information consists of 16 bit. 8 bit contain the input driver information for channel 1 to 8. The remaining 8 bits are used to program a certain operation mode.

Control Byte1: Operation mode and diagnosis select for channels 1 to 8

Data Byte1: ON/OFF information for channel 1 to 8

Serial Output (SO) data consists of 16 bit containing the diagnosis information for channels 1 to 8 with two bits per channel.

DIAG_1: Diagnosis data for channels 1 to 8.

Channel 9 to 16:

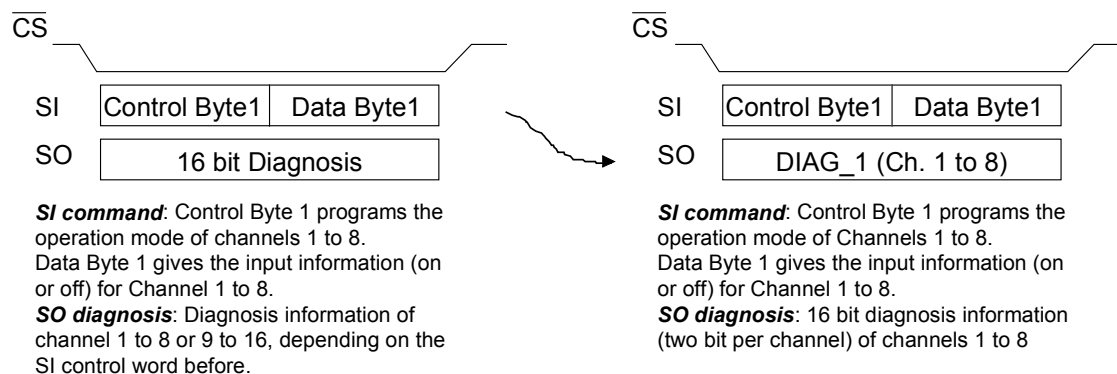
Control Byte2: Operation mode and diagnosis select for channels 9 to 16

Data Byte2: ON/OFF information for channel 9 to 16

DIAG_2: Diagnosis data for channels 9 to 16.

To drive all 16 channels and to get the complete diagnosis data of the TLE 6240 GP a two step access has to be performed as follows:

First access:



The diagram illustrates the transition from a standard SI command to a DIAG_2 command. On the left, the SI command structure shows CS, SI, SO, Control Byte2, Data Byte2, and a 16-bit Diagnosis block. On the right, the DIAG_2 command structure shows CS, SI, SO, Control Byte2, Data Byte2, and a DIAG_2 (Ch. 9 to 16) block. An arrow points from the left structure to the right one.

As mentioned above, the serial input information consist of a control byte and a data byte. Via the control byte, the specific mode of the device is programmable.

MSBLSB
CCCCCCCC DDDDDDDD : 16 bit serial input information
Control ByteData Byte

Ten specific control words are recognised, having the following functions:

No.	SI Control and Data Byte			Function
1	LLLL	LLLL	XXXX XXXX	'Full Diagnosis' (two bits per channel) performed for channels 1 to 8. No change to output states.
2	HHLL	LLLL	XXXX XXXX	State of the eight parallel inputs and '1-bit Diagnosis' for channel 1 to 8 is provided
3	HLHL	LLLL	XXXX XXXX	Echo-function of SPI; SI direct connected to SO
4	LLHH	LLLL	DDDDDDDD	IN1...4 and serial data bits 'OR'ed. 'Full Diagnosis' performed for channels 1 to 8.
5	HHHH	LLLL	DDDDDDDD	IN1...4 and serial data bits 'AND'ed. 'Full Diagnosis' performed for channels 1 to 8.
6	LLLL	HHHH	XXXX XXXX	'Full Diagnosis' (two bits per channel) performed for channels 9 to 16. No change to output states.
7	HHLL	HHHH	XXXX XXXX	State of the eight parallel inputs and '1-bit Diagnosis' for channel 9 to 16 is provided.
8	HLHL	HHHH	XXXX XXXX	Echo-function of SPI; SI direct connected to SO
9	LLHH	HHHH	DDDDDDDD	IN9...12 and serial data bits 'OR'ed. 'Full Diagnosis' performed for channels 9 to 16.
10	HHHH	HHHH	DDDDDDDD	IN9...12 and serial data bits 'AND'ed. 'Full Diagnosis' performed for channels 9 to 16.

Note: Control Byte: Channel Selection via Bit 0 to 3

Bits 0 to 3 = L Channels 1 to 8 selected

Bits 0 to 3 = H Channels 9 to 16 selected

Data byte: 'X' means 'don't care', because this data bits will be ignored

'D' represents the data bits, either being H (= ON) or L (= OFF)

In the following section the different control bytes will be described. X used within the control byte means:

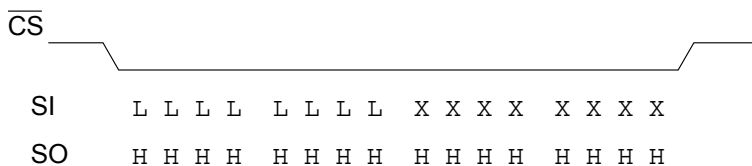
X = L: Command is valid for channels 1 to 8

X = H: Command is valid for channels 9 to 16

1/6. LLLL XXXX - Diagnosis only

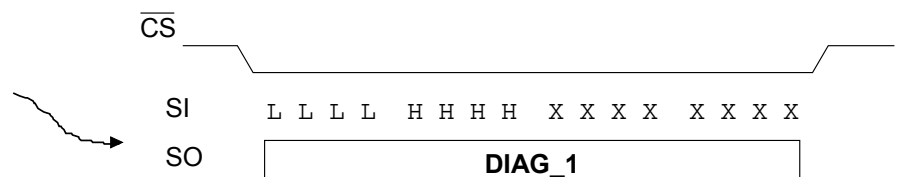
By clocking in this control byte, it is possible to get pure diagnostic information (two bits per channel) in accordance with Figure 1 (page 14). The data bits are ignored, so that the state of the outputs are not influenced. This command is only active once unless the next control command is again "Diagnosis only". Diagnostic information can be read out at any time with no change of the switching conditions.

Example for two consecutive chip select cycles:



SI command: Diagnosis only for channels 1 to 8. No change of the output states

SO diagnosis: No fault, normal function of channels 1 to 8 or 9 to 16 depending on previous SI command



SI command: Diagnosis only for channels 9 to 16. No change of the output states **DIAG_2** provided during next chip select cycle

SO diagnosis: 2 bit diagnosis performed for channels 1 to 8

2/7. HHLL XXXX - Reading back of the eight inputs and '1-bit Diagnosis' provided

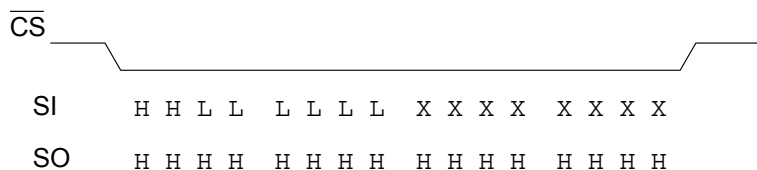
If the TLE 6240 GP is used as bare die in a hybrid application, it is necessary to know if proper connections exist between the μ C-port and parallel inputs. By entering 'HHLL' as the control word, the first eight bits of the SO give the state of the parallel inputs, depending on the μ C signals. By comparing the IN-bits with the corresponding μ C-port signal, the necessary connection between the μ C and the TLE 6240 GP can be verified - i.e. 'read back of the inputs'. The second 8-bits fed out at the serial output contains '1-bit' fault information of the outputs (H = no fault, L = fault). In the expression given below for the output byte, 'FX' is the fault bit for channel X.

MSB LSB

IN12 IN11 IN10 IN9 IN4 IN3 IN2 IN1 FX FX FX FX FX FX FX FX : Serial Output byte

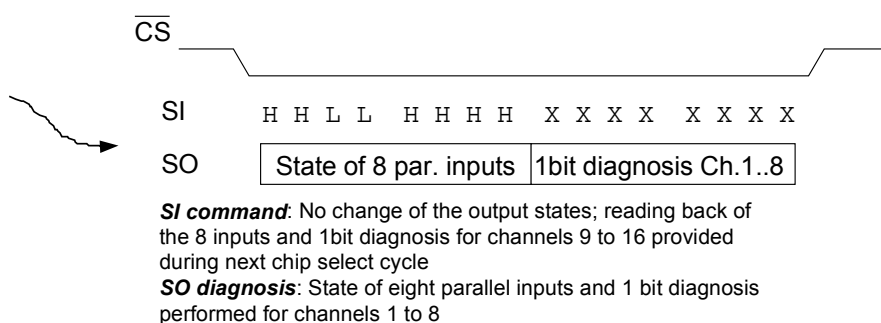
Parallel Input Signals Fault Bits Channels 1 to 8 or 9 to 16

Example for two consecutive chip select cycles:



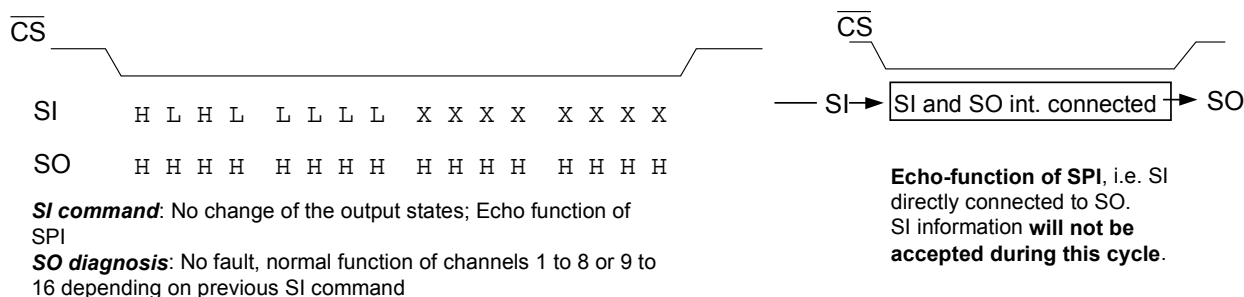
SI command: No change of the output states; reading back of the 8 inputs and 1bit diagnosis for channels 1 to 8

SO diagnosis: No fault, normal function of channels 1 to 8 or 9 to 16 depending on previous SI command



3/8. HLHL XXXX - Echo-function of SPI

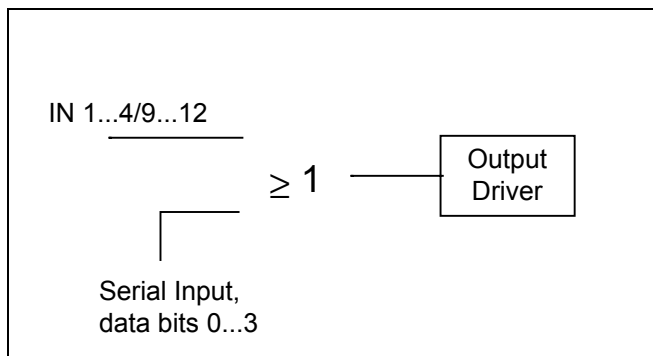
To check the proper function of the serial interface the TLE 6240 GP provides a "SPI Echo Function". By entering HLHL as control word, SI and SO are connected during the next $\overline{CS}$ period. By comparing the bits clocked in with the serial output bits, the proper function of the SPI interface can be verified. This internal loop is **only closed once** (for one $\overline{CS}$ period). The "Echo Function" does not cause any internal processing of data and after the next $\overline{CS}$ signal the SO data is "0" (all registers reset).



4/9. LLHH XXXX DDDDDDDD - OR operation, and 'full diagnosis'

With LLHH LLLL as the control word, each of the input signals IN1...IN4 are 'OR'ed with the corresponding SI data bits.

With LLHH HHHH as the control word, each of the input signals IN9...IN12 are 'OR'ed with the corresponding SI data bits.



This OR operation enables the serial interface to switch the channel ON, even though the corresponding parallel input might be in the off state.

SPI Priority for ON-State

Also parallel control of the outputs is possible without an SPI input.

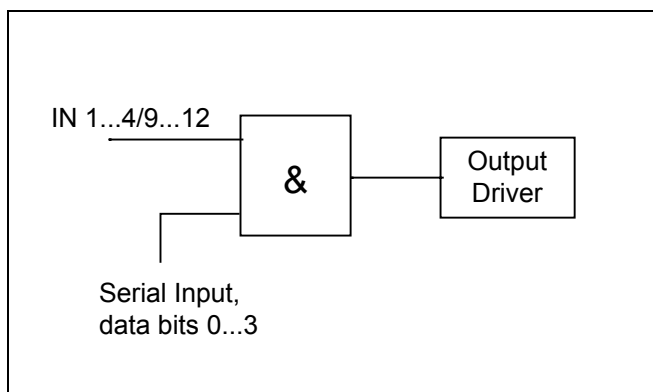
The OR-function is the default Boolean operation if the device restarts after a Reset, or when the supply voltage is switched on for the first time.

If the OR operation is programmed it is latched until it is overwritten by the AND operation.

5/10. HHHH XXXX DDDDDDDD - AND operation, and 'full diagnosis'

With HHHH LLLL as the control word, each of the input signals IN1...IN4 are 'AND'ed with the corresponding SI data bits.

With HHHH HHHH as the control word, each of the input signals IN9...IN12 are 'AND'ed with the corresponding SI data bits.



The AND operation implies that the output can be switched off by the SPI data bit input, even if the corresponding parallel input is in the ON state.

SPI Priority for OFF-state

This also implies that the serial input data bit can only switch the output channel ON if the corresponding parallel input is in the ON state.

If the AND operation is programmed it is latched until it is overwritten by the OR operation.

Control words beside No. 1- 10

Not specified Control words are not executed (cause no function) and the shift register (SO Data) is reset after the $\overline{\text{CS}}$ signal (all "0").

Example for an access to channel 1 to 8:

LLHH LLLL HLLH LLLH: OR operation between parallel inputs and data bits, i.e channel 1, 5 and 8 will be switched on.

The next command is now: **LHHH LLLL HHHH LLLL**

LHHH LLLL as command word has no special meaning and will not be accepted. The output states will not be changed and the shift register will be reset (at the next $\overline{\text{CS}}$ SO Data all "0").

Diagnostics

FAULT - Fault pin. There is a general fault pin (open drain) which shows a high to low transition as soon as an error occurs for any one of the sixteen channels. This fault indication can be used to generate a μC interrupt. Therefore a 'diagnosis' interrupt routine need only be called after this fault indication. This saves processor time compared to a cyclic reading of the SO information.

As soon as a fault occurs, the fault information is latched into the diagnosis register. A new error will over-write the old error report. Serial data out pin (SO) is in a high impedance state when $\overline{\text{CS}}$ is high. If $\overline{\text{CS}}$ receives a LOW signal, all diagnosis bits can be shifted out serially.

For full diagnosis there are two diagnostic bits per channel configured as shown in Figure 1.

Normal function: The bit combination **HH** indicates that there is no fault condition, i.e. normal

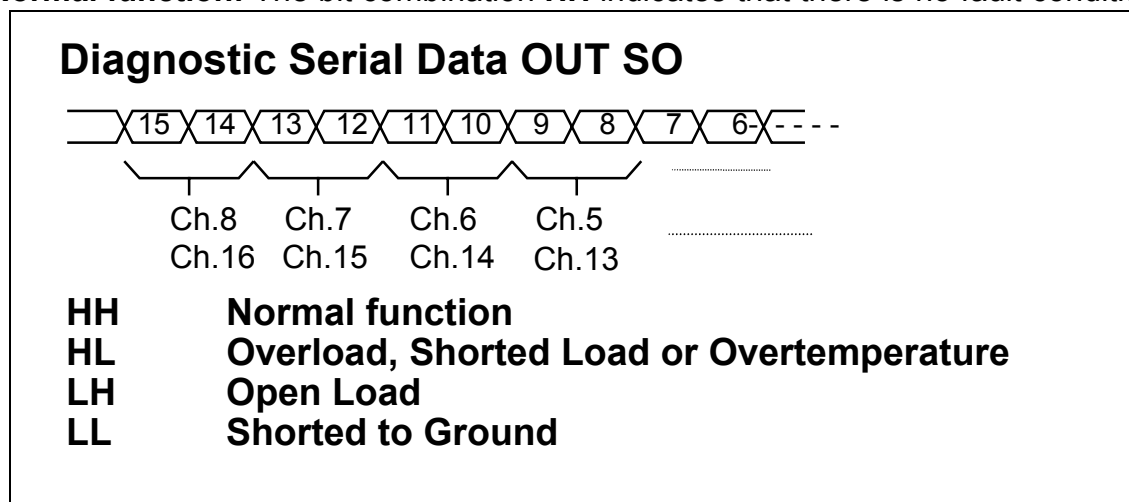


Figure 1: Two bits per channel diagnostic feedback function.

Overload, Short Circuit to Battery (SCB) or Overtemperature: **HL** is set when the current limitation gets active, i.e. there is a overload, short to supply or overtemperature condition.

Open load: An open load condition is detected when the drain voltage decreases below 3 V (typ.). **LH** bit combination is set.

Short Circuit to GND: If a drain to ground short circuit exists and the drain to ground current exceeds 100 μA , short to ground is detected and the **LL** bit combination is set.

A definite distinction between open load and short to ground is guaranteed by design.

The standard way of obtaining diagnostic information is as follows:

Clock in serial information into SI pin and wait approximately 150 μs to allow the outputs to settle. Clock in the identical serial information once again - during this process the data coming out at SO contains the bit combinations representing the diagnosis conditions as described in figure 1.

Reset of the Diagnosis Register

The diagnosis register is reset after reading the diagnosis data (after the falling $\overline{\text{CS}}$ edge). This is done for channels 1-8 and channels 9-16 separately depending on the previous command.

By means of the control byte it is possible either to:

- a) control the outputs according to the data byte, as well as being able to read the diagnostic information (two bits per channel)
- or b) purely get diagnostic information without changing the state of the outputs
- or c) read back the parallel inputs plus a simple diagnosis (one bit per channel)
- or d) SPI "Echo Function" as a diagnosis of proper SPI function

a) Serial Control of Outputs

- **LLHHLLLL LHLHHLLL**

Control Byte
Data Byte

SI information: OR-operation valid for channels 1 to 8.

SO: 16 bit diagnosis for channels 1 to 8 performed during next chip select cycle.

- **LLHHHHHH LHLHHLLL**

Control Byte
Data Byte

SI information: OR-operation valid for channels 9 to 16

SO: 16 bit diagnosis for channels 9 to 16 performed during next chip select cycle.

- **HHHHLLLL LHLHHLLL**

Control Byte
Data Byte

SI information: AND-operation valid for channels 1 to 8

SO: 16 bit diagnosis for channels 1 to 8 performed during next chip select cycle.

- **HHHHHHHH LHLHHLLL**

Control Byte
Data Byte

SI information: AND-operation valid for channels 9 to 16

SO: 16 bit diagnosis for channels 9 to 16 performed during next chip select cycle.

b) Diagnosis Only

- **LLLLLLLL XXXXXXXX**

Control Byte
Data Byte

SI information: Full diagnosis for channels 1 to 8. No change of output states.

SO: 16 bit diagnosis for channels 1 to 8 performed during next chip select cycle.

- **LLLLHHHH XXXXXXXX**

Control Byte
Data Byte

SI information: Full diagnosis for channels 9 to 16. No change of output states.

SO: 16 bit diagnosis for channels 9 to 16 performed during next chip select cycle.

c) Read back of parallel inputs plus simple diagnosis

- **HHLLLLLL XXXXXXXX :**

Control Byte
Data Byte

SI information: No change of the output states. Read back of parallel inputs and 1 bit diagnosis for channels 1 to 8.

SO: State of eight inputs plus 1 bit diagnosis for channel 1 to 8 during next chip select cycle.

- **HHLLHHHH XXXXXXXX**

Control Byte
Data Byte

SI information: No change of the output states. Read back of parallel inputs and 1 bit diagnosis for channels 9 to 16.

SO: State of eight inputs plus 1 bit diagnosis for channel 9 to 16 during next chip select cycle.

d) SPI Echo function

- **HLHLLLLL XXXXXXXX :**

Control Byte
Data Byte

SI information: Echo function of SPI interface. No change of the output states.

SO: During next chip select cycle the SI bits clocked in appear directly at SO because of an internal connection for this cycle

- **HLHLHHHH XXXXXXXX**

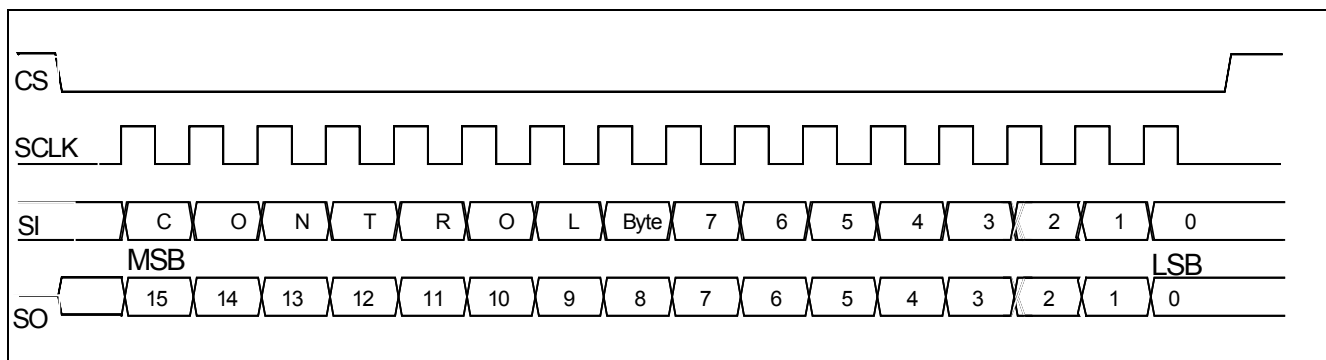
Control Byte
Data Byte

SI information: Echo function of SPI interface. No change of the output states.

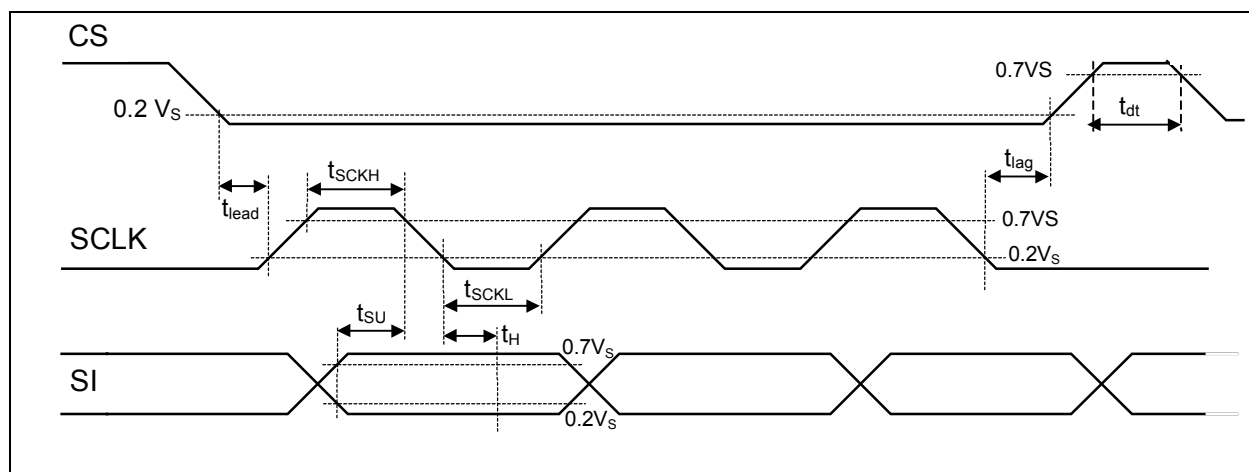
SO: During next chip select cycle the SI bits clocked in appear directly at SO because of an internal connection for this cycle

Timing Diagrams

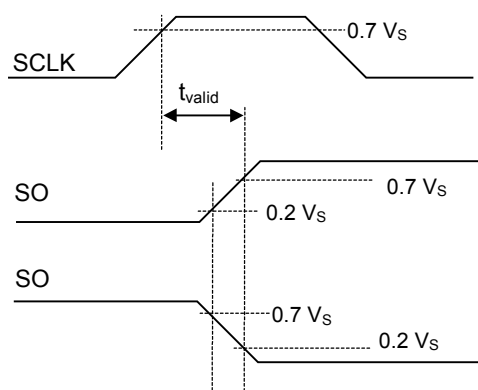
Serial Interface



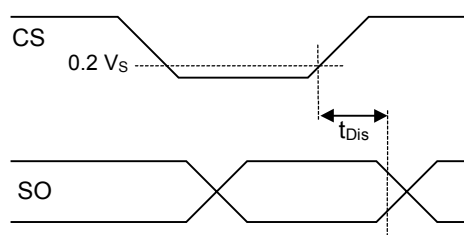
Input Timing Diagram



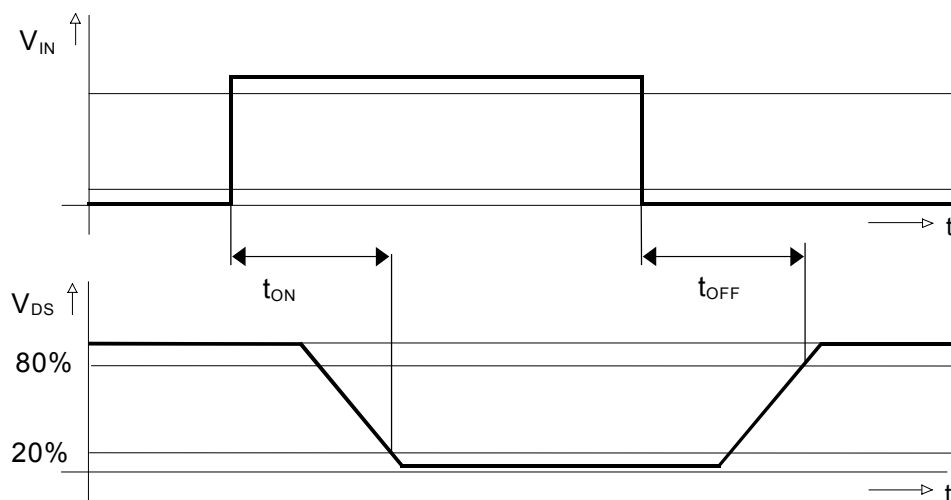
SO Valid Time Waveforms



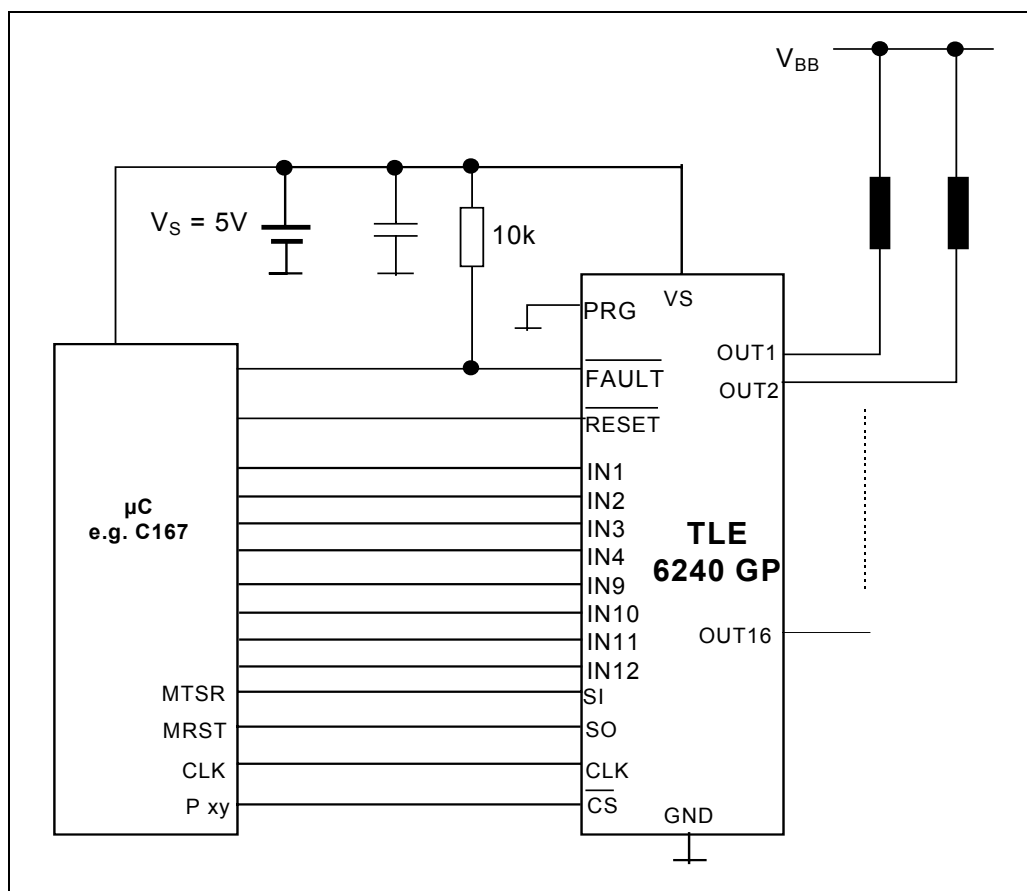
Enable and Disable Time Waveforms



Power Outputs



Application Circuit



Typical electrical Characteristics

Drain-Source on-resistance

$$R_{DS(ON)} = f(T_j) ; V_s = 5V$$

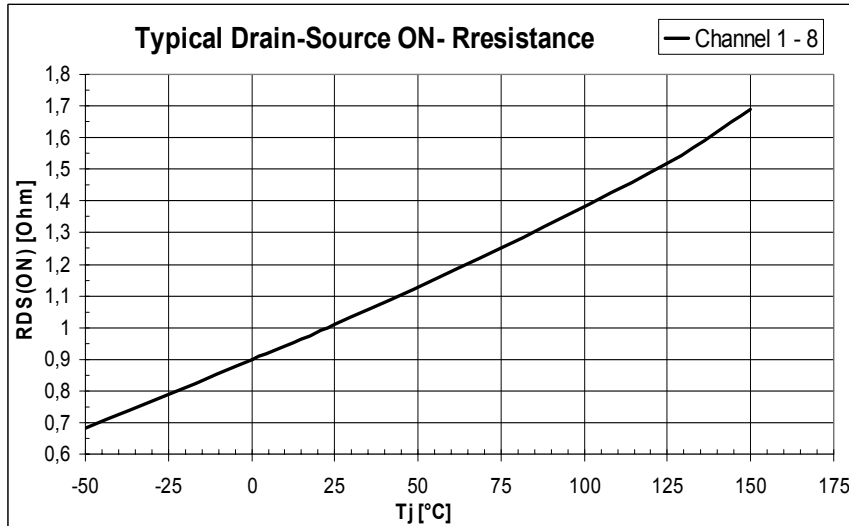


Figure 2 :
Typical ON Resistance ver-
sus Junction-Temperature

Channel 1-8

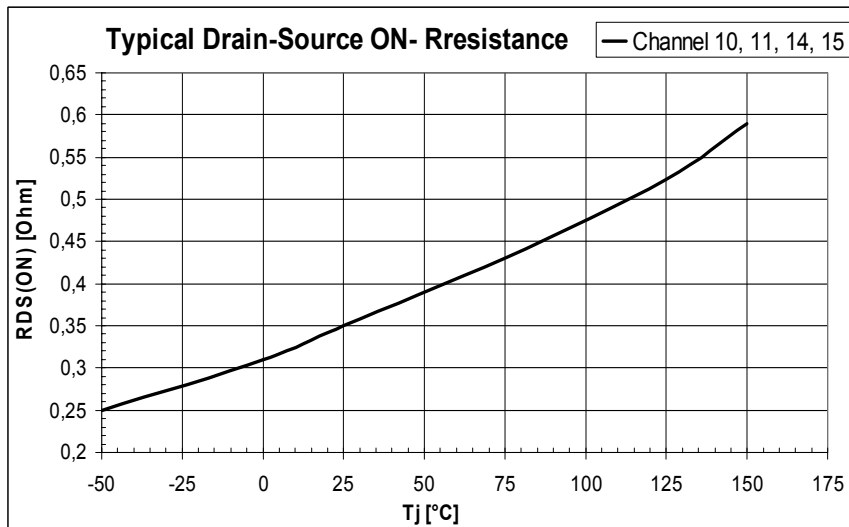


Figure 3 :
Typical ON Resistance ver-
sus Junction-Temperature

Channel 10, 11, 14, 15

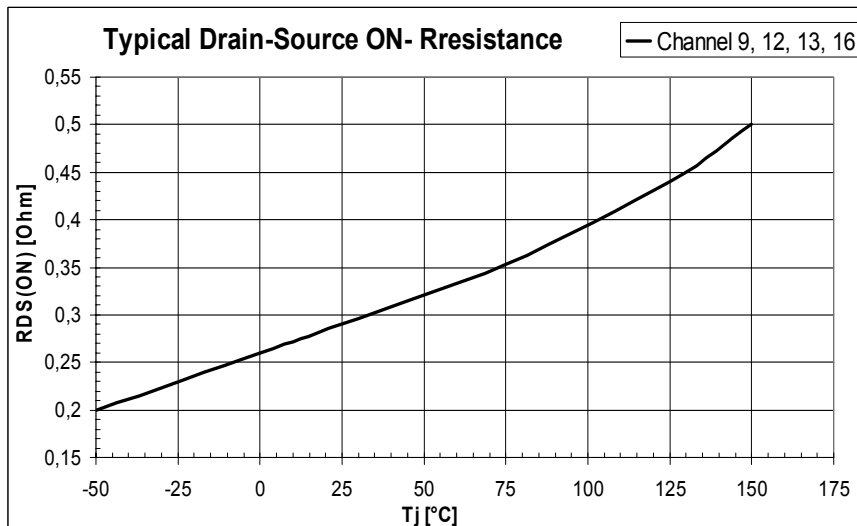


Figure 4 :
Typical ON Resistance ver-
sus Junction-Temperature

Channel 9, 12, 13, 16

Output Clamping Voltage

$$V_{DS(AZ)} = f(T_J) ; V_s = 5V$$

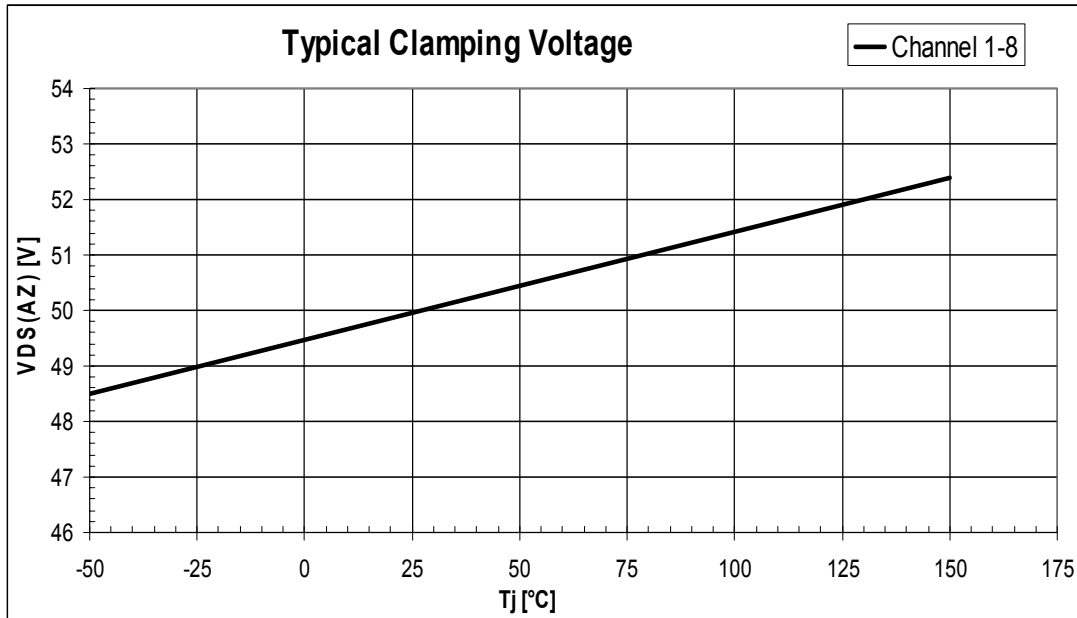


Figure 5 : Typical Clamping Voltage versus Junction-Temperature
Channel 1-8

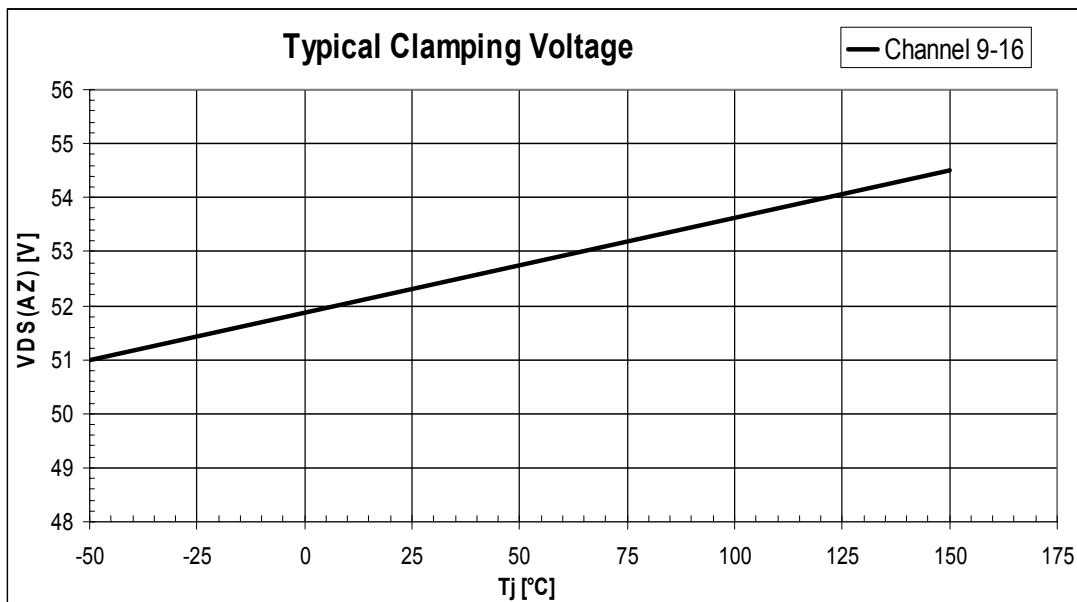
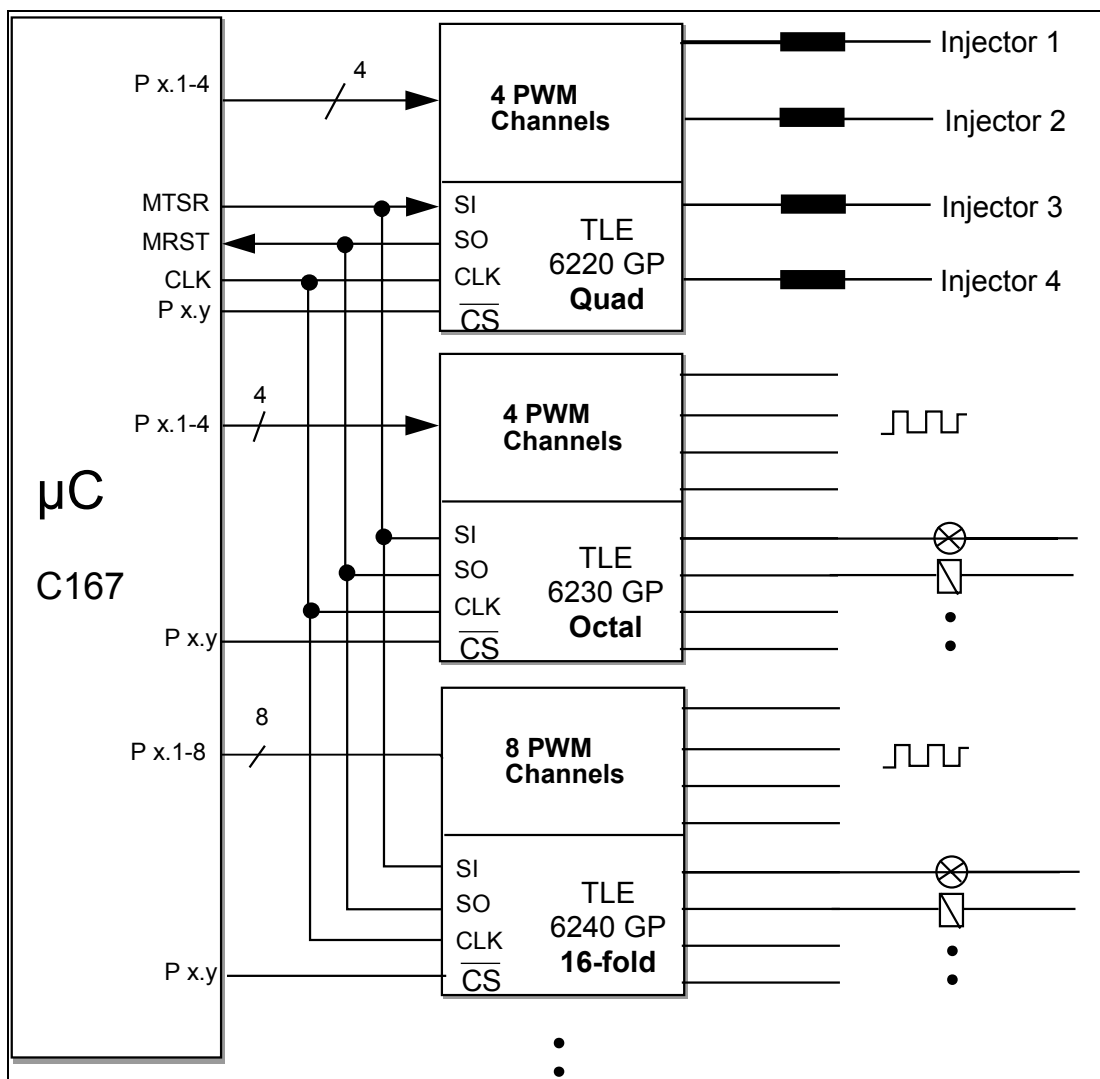


Figure 6 : Typical Clamping Voltage versus Junction-Temperature
Channel 9-16

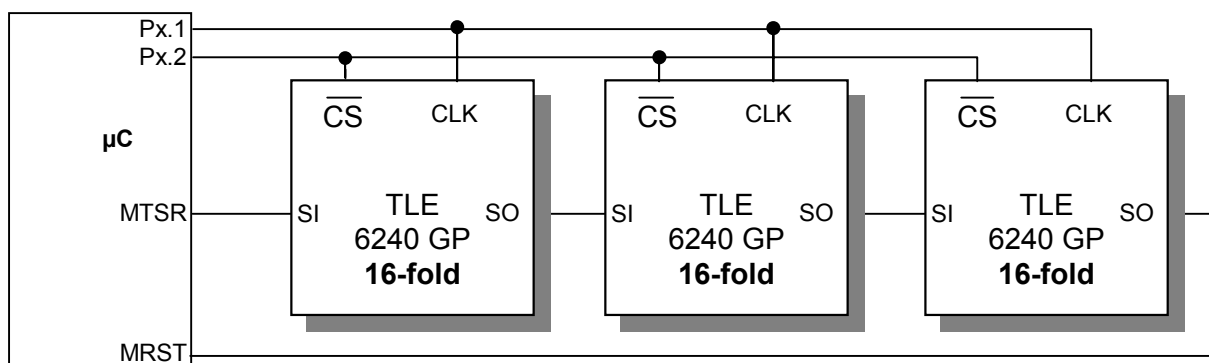
Parallel SPI Configuration

Engine Management Application

TLE 6240 GP in combination with TLE 6230 GP (octal switch) for relays and general purpose loads and TLE 6220 GP to drive the injector valves. This arrangement covers the numerous loads to be driven in a modern Engine Management/Powertrain system. From 28 channels in sum 16 can be controlled direct in parallel for PWM applications.



Daisy Chain Application TLE 6240 GP



Package and Ordering Code

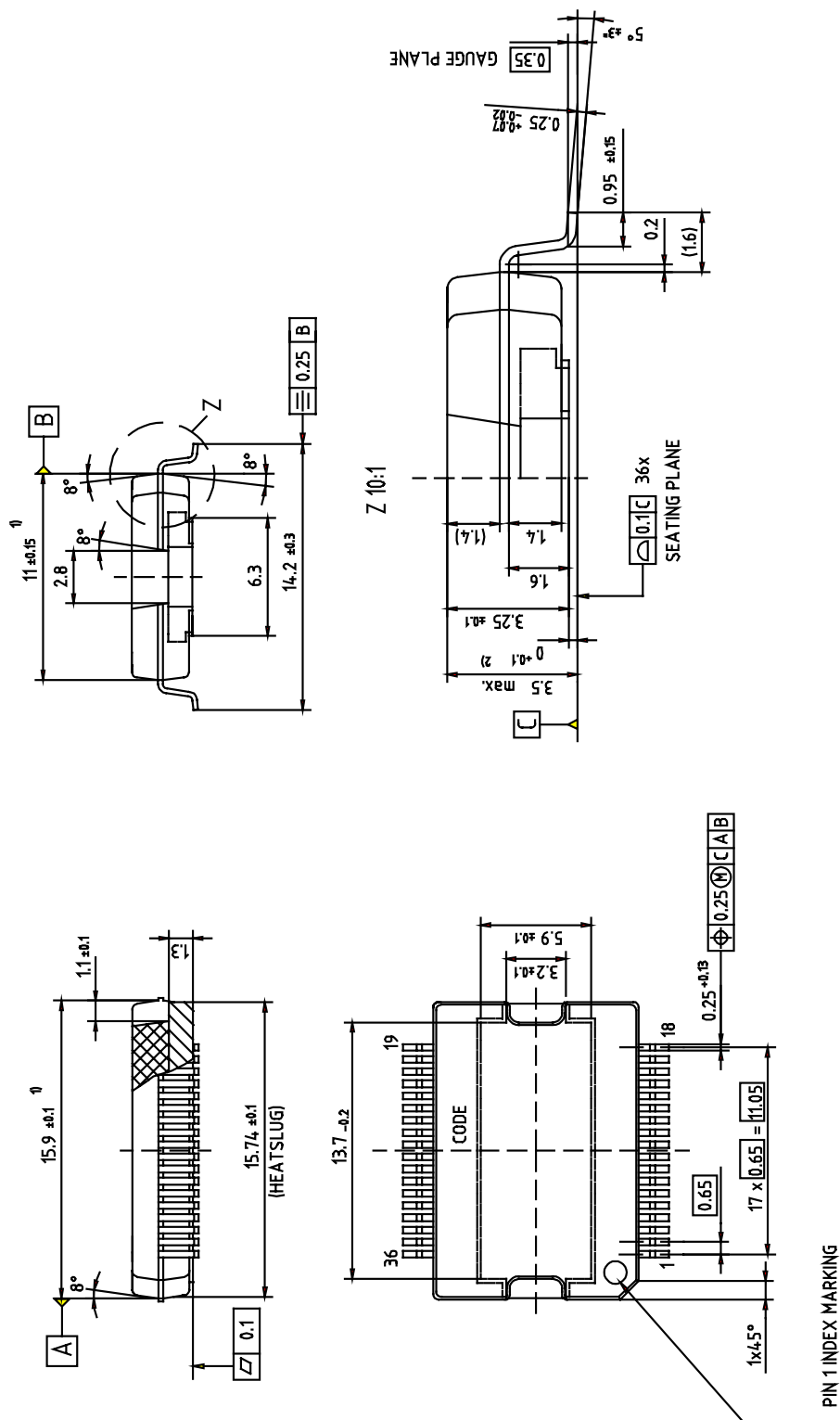
(all dimensions in mm)

P-DSO 36-12

Ordering Code

TLE 6240 GP

Q67007-A9470



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